Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/728,426	MARPE ET AL.
Examiner	Art Unit
Yuzhen Ge	2624

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout IEEE Xplore - See search session history printout	3/29/2007	YG
IEEE Xplore - See search session history printout	3/29/2007	YG
Google scholar	3/29/2007	YG